



DPC: 24 / 30499096 DC

BSI Group Headquarters

389 Chiswick High Road London W4 4AL

Tel: +44 (0)20 8996 9000

Fax: +44 (0)20 8996 7400

www.bsigroup.com

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Responsible committee: EPL/47 Semiconductors

Interested committees:

Title: BS EN IEC 63602 Guidelines for Representing Switching Losses of SIC MOSFETs in Datasheets (Fast track)

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- iii) requires additional national guidance or information

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Responsible Committee Secretary: **Committee Service Centre (BSI)**
Direct tel: **020 8996 7009**
E-mail: csc@bsigroup.com

Introduction

This draft standard is based on national and international discussions. Your comments on this draft are invited and will assist in the preparation of the consequent standard.

For international standards, comments will be reviewed by the relevant UK national committee before sending the consensus UK vote and comments to the international committee, which will then decide appropriate action. If the international standard is approved, it is usual for the text to be published as a British Standard.

For national standards, comments will be reviewed by the relevant UK national committee and the resulting standards published as a British Standard.

UK Vote

Please indicate whether you consider the UK should submit a negative (with supporting technical reasons) or positive vote on this draft. Please indicate if you are aware of any reason why this draft standard should not be published as a British Standard.

Submission of Comments

- **Annotated drafts are not acceptable and will be rejected.**
- All comments should be submitted online at <https://standardsdevelopment.bsigroup.com/>. You will need to register in order to comment.

Template for comments and secretariat observations

Date: xx/xx/20xx	Document: ISO/DIS xxxx
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1	2	(3)	4	5	(6)	7
MB	Clause No./ Subclause No./Annex (e.g. 3.1)	Paragraph/Figure/ Table/Note	Type of comment	Commend (justification for change) by the MB	Proposed change by the MB	Secretariat observations on each comment submitted
	3.1	Definition 1	ed	Definition is ambiguous and needs clarifying.	Amend to read '...so that the mains connector to which no connection...'	
	6.4	Paragraph 2	te	The use of the UV photometer as an alternative cannot be supported as serious problems have been encountered in its use in the UK.	Delete reference to UV photometer.	



COMMITTEE DRAFT FOR VOTE (CDV)

PROJECT NUMBER:

IEC 63602 ED1

DATE OF CIRCULATION:

2024-10-04

CLOSING DATE FOR VOTING:

2024-12-27

SUPERSEDES DOCUMENTS:

IEC TC 47 : SEMICONDUCTOR DEVICES

SECRETARIAT:

Korea, Republic of

SECRETARY:

Mr Cheolung Cha

OF INTEREST TO THE FOLLOWING COMMITTEES:

TC 91, TC 104

HORIZONTAL FUNCTION(S):

ASPECTS CONCERNED:

☐ SUBMITTED FOR CENELEC PARALLEL VOTING☒ NOT SUBMITTED FOR CENELEC PARALLEL VOTING

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Recipients of this document are invited to submit, with their comments, notification of any relevant patent rights of which they are aware and to provide supporting documentation.

Recipients of this document are invited to submit, with their comments, notification of any relevant "In Some Countries" clauses to be included should this proposal proceed. Recipients are reminded that the CDV stage is the final stage for submitting ISC clauses. (SEE [AC/22/2007](#) OR [NEW GUIDANCE DOC](#)).

TITLE:

Guidelines for Representing Switching Losses of SIC MOSFETs in Datasheets (Fast track)

PROPOSED STABILITY DATE: 2028

NOTE FROM TC/SC OFFICERS:

This CDV is based upon JEDEC document JEP187 (title: Guidelines for Representing Switching Losses of SIC MOSFETs in Datasheets) and is circulated according to the IEC fast-track procedure (see F.2 of ISO/IEC Directives, Part 1, 2024). This document is proposed by the US National Committee and TC 47/WG 8 at the November 2023 meeting approved fast-track procedure and was presented to TC 47 Plenary meeting in November 2023. This project is allocated to TC 47/WG 8 and Project Leader: Peter Friedrichs.

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

GUIDELINES FOR REPRESENTING SWITCHING LOSSES OF SIC MOSFETS IN DATASHEETS**FOREWORD**

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The text of this International Standard is based on the following documents:

FDIS	Report on voting
XX/XX/FDIS	XX/XX/RVD

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "<http://webstore.iec.ch>" in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.